## Notice of References Cited Application/Control No. 10/532,988 Examiner Eric Loonan Applicant(s)/Patent Under Reexamination EBARA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0177215	09-2004	Nagamasa et al.	711/103
*	В	US-2001/0019614	09-2001	Madoukh , Ashraf	380/277
*	C	US-5,721,781	02-1998	Deo et al.	705/67
	D	US-			
	E	US-			
(I = 1)	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q			3 - 3		
	R					
	s					
	T.	,				

## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	>					
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	x					

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